Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10507180	DE BETHUNE ET AL.
Examiner	**Art Unit**
JENNIFER Y CHO	1621

ORIGINAL		INTERNATIONAL CLASSIFICATION	
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED
562	430	C 07C 315/00 (2006.01.01)	
		C 07C 317/00 (2006.01.01)	
CROSS REFERENCE(S)		C 07C 321/00 (2006.01.01)	
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)	C 07C 323/00 (2006.01.01)	
562	432	C 07C 381/00 (2006.01.01)	

/JENNIFER Y CHO/ (Assistant Examiner)	5/6/08 (Date)		**Total Claims Allowed:** 4
/Yvonne Eyler/ (Primary Examiner)	5/16/08 (Date)	O.G. Print Claim(s) 20	O.G. Print Figure none